

Materials List for:

Characterization of SiN Integrated Optical Phased Arrays on a Wafer-Scale Test Station

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Materials

Name	Company	Catalog Number	Comments
25 ch electrical Probe	Cascade Microtech	InfinityQuad 25ch	
35 mm CCD sensor	Allied Vision	Prosilica GT 6600	
Arduino uno	Arduino	A100066	
laser	Qphotonics	QFLD-905-10S	
optical fibre	Corning	HI780	
polarization controller	ThorLabs	FPC023	
prober station	Cascade Microtech	Elite 300	